

Listing of Claims:

- [illegible]

9. (Previously Presented) The method of claim 1, wherein the scanning probe microscopy is atomic force microscopy, scanning tunneling microscopy, lateral force microscopy, chemical force microscopy, force modulation imaging, magnetic force microscopy, high frequency magnetic force microscopy, magnetoresistive sensitivity mapping, electric force microscopy, scanning capacitance microscopy, scanning spreading resistance microscopy, tunneling atomic force microscopy or conductive atomic force microscopy.

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17. (Original) The method of claim 1, further comprising transforming the molecular nanocode to form a decompressed nanocode.

18. (Previously Presented) The method of claim 1, wherein the feature tag comprises a barcode segment.

19. (Previously Presented) The method of claim 1, wherein the feature tag comprises a header segment and an encoding segment.

20-36. (Canceled)